

<b>Notice of References Cited</b>	Application/Control No. 10/604,289	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
	Examiner TUAN A. PHAM	Art Unit 2618	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0037738	03-2002	Wycherley et al.	455/550
*	B	US-6,097,943	08-2000	Nordwall, Thomas	455/418
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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